SHEET 1 OF 1

				ATTY DOCKET NO.		SERIAL	MO.		
Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE							
			251280US2RD 10/813,110						
LIGHT OF DESCRIPTION OF BUY ADDITIONALT				APPLICANT					
LIST OF REFERENCES CITED BY APPLICANT				Takamitsu SUNAOSHI					
				FILING DATE		GROUP			
				March 31, 2004		3736			
	U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUB FILING DATE IF APPROPRIATE				
	AA								
	AB								
	AÇ		•						
	AD								
	AE								
	AF								
	AG		<u>.</u>				••••		
	AH	,					-		
-	Al				 				
	A				1				
-	AK								
					 	-			
	AL				 -			·	
	AM				ļ				
	AN	<u>. </u>			_				
			FO	REIGN PATENT DOCUMENTS					
		DOCUMENT DATE COUNTRY				TRANSLATION YES NO			
	AO				***				
	ΑP								
	AQ								
	AR							V3	
	AS					<u> </u>			
	AT								
	AU			•	-				
	AV		•		***				
		OTUED DE	EEDENCES	Including Author, Title, Date, Pertinen	f Ponce ^	tc \			
				' <u>-</u>	r i añesi e			· · ·	
CIB	AW	Makoto JINNO, et al., U.S. Serial No. 11/090,163, filed March 28, 2005.							
	AX								
	AY								
	AZ	Additional References sheet(s) attached							
Examiner	Examiner Tuptal Barris Date Considered 3 Aug. 2005							16.2005	
*Examiner: in	itial it n and no	eference is considered, of considered, of considered. Include co	whether or no py of this for	t citation is in conformance with MPEP 6 n with next communication to applicant.	09; Draw II	ne through			

		:				SHE	ET 1 OF	1		
Form PTO 1449 (Modified)		U.S. DEPARTMENT (OF COMMERCE DEMARK OFFICE	ATTY DOCKET NO.				SERIAL NO.		
				251280US2RD	10/813,110					
LIST OF	OCCEI	RENCES CITED BY API	ECANO	APPLICANT T-1		•				
LIST OF	KEFEF	CENCES CITED BY AFT	PEICHOPA!	Takamitsu SUNAOSHI						
		, (ויי שונה ה	FILING DATE	GROUP					
MM 5 0 pm 2			March 31, 2004	3736						
		\a_		U.S. PATENT DOCUMENTS						
EXAMINER INITIAL		DOCUMENTATE NUMBER	RAGEATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	E		
	AA	· ·								
	AB	·			1					
	AC				1					
	AD		 		1					
	AE		 	1.	+					
	AF		+	 	+					
	AG	,	 	 	+	 		_		
	AH		 		+	+ +				
	Al		1	 	+	 	-			
	AJ			 	+					
	AK	-		,	+ .					
			 	<u> </u>	-	 				
·	AL	· · · · · · · · · · · · · · · · · · ·	 	 	 					
	AM		 	 	+	\vdash		_		
	AN	<u> </u>	<u> </u>	<u> </u>						
<u> </u>		· · · · · · · · · · · · · · · · · · ·	FO	PREIGN PATENT DOCUMENTS				_		
		DOCUMENT NUMBER	DATE	COUNTRY		TRANSLATION YES N				
(MP_	AO ·	8-99278	04/16/1996	JAPAN (with English Abstract)			х	_		
(DR)	AP	4-360777	12/14/1992	JAPAN (with English Abstract)			x			
	AQ.						•	_		
•	AR		 		••••			_		
	AS			1						
	AT				•			_		
	AU				•	 		_		
	AV		 	 		 				
	•	OTHER RE	EFERENCES (Including Author, Title, Date, Pertinen	nt Pages, e	tc.)				
	AW									
	AX				•		·			
	AY									
	AZ				Additional References sheet(s) attached					
Examiner	Crustal James Date Considered 29 July 1					29 July 109	っる			
*Examiner: In conformance	itial it	eference is considered.	whether or no	ot citation is in conformance with MPEP 6 n with next communication to applicant.	i09; Draw li	ne through		_		

Form PTO 1449 U.S. DEPARTMENT OF COMMERCE (Modified) PATENT AND TRADEMARK OFFICE			ATTY DOCKET NO.		SERIAL NO.				
			251280US2RD 10/813,110			110			
		OIPE	- ZC	APPLICANT					
LIST OF REFERENCES CITED BY APPLICANT			Takamitsu SUNAOSHI						
AUG 1 6 2004 2				FILING DATE		GROUP			
			<u> </u>	March 31, 2004					
		A LRAI	, RPT	U.S. PATENT DOCUMENTS					
EXAMINER				NAME CLASS		SUB FILING DATE			
INITIAL	<u> </u>	NUMBER	DATE	NAME	CDASS	CLASS	IF APPROPRIATE		
	AA								
	AB								
	AC								
	AD								
	AE								
	AF								
	AG								
	AH								
	AI								
	AJ			·					
	AK								
	AL					1			
	АМ								
	AN								
	*		FO	REIGN PATENT DOCUMENTS		<u> </u>			
	ľ	DOCUMENT				<u> </u>	TRANSLATION		
~1		NUMBER	DATE	COUNTRY		YES NO			
<u> </u>	AO	8-215204	08/27/1996	JAPAN (with English Abstract)			X		
(36)	AP	2003-53685	02/26/2003	JAPAN (with English Abstract)		L	X		
	AQ								
	AR		į						
	AS								
	AT								
	ΑU								
	AV								
		OTHER F	REFERENCES (Including Author, Title, Date, Pertine	nt Pages, e	tc.)			
									
	AW								
	AX	i							
	ļ				·				
	AY								
	AZ				Addi	Additional References sheet(s) attached			
Examiner	Chi	ptal Durned 29 July 105				29 July '05			
*Examiner: Ir conformance	nitial if r	eference is considered	d, whether or no	t citation is in conformance with MPEP (n with next communication to applicant.	609; Draw li	ne through			